

<b>Notice of References Cited</b>	Application/Control No. 10/725,254	Applicant(s)/Patent Under Reexamination ZALEWSKI ET AL.	
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**U.S. PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	A	US-5,599,075 A	02-1997	Hara et al.	303/143
	B	US-5,804,935 A	09-1998	Radev, Vladimir	318/139
	C	US-5,927,426 A	07-1999	Hall et al.	180/249
	D	US-6,458,056 B1	10-2002	Brown et al.	475/204
	E	US-6,464,612 B2	10-2002	Frost, Barry L.	475/288
	F	US-6,598,946 B2	07-2003	Nagae, Akira	303/190
	G	US-6,427,550 B1	08-2002	Bowen, Thomas C.	74/336R
	H	US-2002/0107628 A1	08-2002	Sakakiyama, Ryuzo	701/89
	I	US-2002/0142878 A1	10-2002	Bansbach et al.	475/204
	J	US-2002/0144851 A1	10-2002	Porter, Fred C.	180/247
	K	US-2002/0153770 A1	10-2002	Matsuno et al.	303/146
	L	US-2002/0180262 A1	12-2002	Hara et al.	303/119.1
	M	US-			

**FOREIGN PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	O					
	P					
	Q					
	R					
	S					
	T					

**NON-PATENT DOCUMENTS**

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
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	V	
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	X	

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